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100 12 JAN 2006

SHIGA7.041APC

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

Masudo et al.

Appl. No.

Unknown

Filed

: Herewith

For

: POSITIVE PHOTORESIST

COMPOSITIONA DN METHOD OF FORMING RESIST PATTERN

Examiner

Unknown

Group Art Unit

Unknown

PRELIMINARY AMENDMENT

Mail Stop Amendment

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Preliminary to examination on the merits, please amend the above-captioned U.S. National Phase Application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks/Arguments begin on page 6 of this paper.